

#### **Feature**

- Precision MEMS process
- High performance, shielded, Micro-cavity structure
- Silicon substrate, 50Ω CPW output
- Au wire bonding, for MCM applications

# **Environmental Specifications**

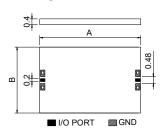
Operating Temperature	-55℃~+85℃	
Storage Temperature	-55℃~+125℃	
Max. Input Power	35dBm	

# Electrical Specifications( $T_A = +25^{\circ}C$ )

Parameter	Min.	Тур.	Max.	Unit
Center Freq. (f₀)	-	8.25	-	GHz
Pass Band	8.1	-	8.4	GHz
Ripple in Pass band	-	-	1	dB
Insertion Loss @ fo	-	-	3.5	dB
Return Loss	13	-	-	dB
Out of band	≥30@7.7GHz&8.75GHz			dB
Attenuation	≥40@7.6GHz&8.85GHz			dB
Group Delay Variation	≤1@8.1~8.4GHz			ns
Linear Phase	≤±4@8.1~8.4GHz			٥

S2P file name: SiMS8R2-R35-6D3.s2p

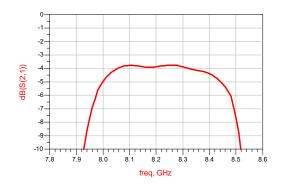
# **Outline Drawing**



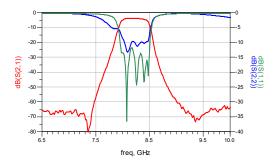
Symbol	Value (mm)			
	Min.	Nominal	Max.	
А	9.3	-	9.5	
В	6.7	-	6.8	

## **Typical Test Curves**

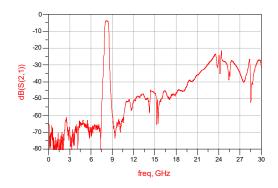
Insertion Loss VS Frequency (T<sub>A</sub>=25°C)



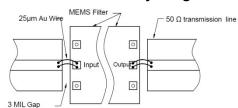
Insertion Loss & Return Loss VS Frequency (T<sub>A</sub>=25°C)



Broadband Insertion Loss VS Frequency (T<sub>A</sub>=25°C)

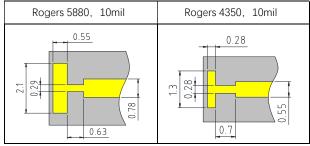


#### **Recommended Assembly Diagrams**



### **Application Notes:**

- 1. The chip is back-metalized and can be die mounted with AuSn eutectic performs or with electrically conductive epoxy (for example ME8456).
- 2. The die should be assembled on carriers like Kovar or Mu-Cu which have same Coefficient of thermal expansion. (2.9ppm/ $^{\circ}$ C) with Silicon, thickness 0.2mm max.
- 3. Handle the chips in a clean environment. DO NOT attempt to clean the chip using liquid cleaning systems.
- 4. Handle the chip along the edges with a vacuum collet or with a sharp pair of bent tweezers.
- 5. Recommended to use T structure as below for bonding.



6. If you have any questions, please contact us.